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Notice of References Cited	Application/Control No. 09/759,414	Applicant(s)/Patent Under Reexamination LI, ZHE	
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	C	US-5,469,367	11-1995	Puri et al.	716/18
	D	US-5,923,569	07-1999	Kumashiro et al.	716/7
	E	US-5,752,000	05-1998	McGeer et al.	703/14
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